# International Rectifier

# IRF4905SPbF IRF4905LPbF

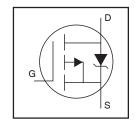
#### **Features**

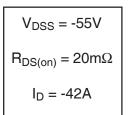
- Advanced Process Technology
- Ultra Low On-Resistance
- 150°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- Some Parameters Are Different from IRF4905S
- Lead-Free

### **Description**

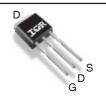
Features of this design are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of other applications.

### HEXFET® Power MOSFET









D <sup>2</sup> Pak
IRF4905SPbF

TO-262 IRF4905LPbF

G	D	S		
Gate	Drain	Source		

#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	-70	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	-44	Α
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	-42	
I <sub>DM</sub>	Pulsed Drain Current ①	-280	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	170	W
	Linear Derating Factor	1.3	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy®	140	mJ
E <sub>AS</sub> (Tested )	Single Pulse Avalanche Energy Tested Value ®	790	
I <sub>AR</sub>	Avalanche Current ①	See Fig.12a, 12b, 15, 16	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ©		mJ
$T_{J}$	Operating Junction and	-55 to + 150	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw ⑦	10 lbf•in (1.1N•m)	

#### **Thermal Resistance**

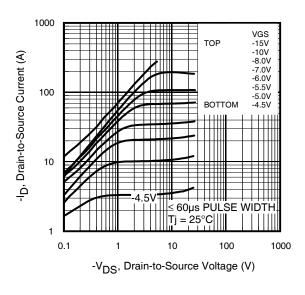
	Parameter	Typ.	Max.	Units	
$R_{\theta JC}$	Junction-to-Case ®		0.75		
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount, steady state) ②®		40		

### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-55			V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.054		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			20	mΩ	V <sub>GS</sub> = -10V, I <sub>D</sub> = -42A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$
gfs	Forward Transconductance	19			S	V <sub>DS</sub> = -25V, I <sub>D</sub> = -42A
I <sub>DSS</sub>	Drain-to-Source Leakage Current			-25	μA	V <sub>DS</sub> = -55V, V <sub>GS</sub> = 0V
				-200		$V_{DS} = -44V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = -20V
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = 20V$
$Q_g$	Total Gate Charge		120	180		I <sub>D</sub> = -42A
$Q_{gs}$	Gate-to-Source Charge		32		nC	$V_{DS} = -44V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		53			V <sub>GS</sub> = -10V ③
t <sub>d(on)</sub>	Turn-On Delay Time		20			V <sub>DD</sub> = -28V
t <sub>r</sub>	Rise Time		99			I <sub>D</sub> = -42A
$t_{d(off)}$	Turn-Off Delay Time		51		ns	$R_G = 2.6 \Omega$
t <sub>f</sub>	Fall Time		64			V <sub>GS</sub> = -10V ③
L <sub>S</sub>	Internal Source Inductance		7.5		nΗ	Between lead,
						and center of die contact
C <sub>iss</sub>	Input Capacitance		3500			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		1250			$V_{DS} = -25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		450		pF	f = 1.0MHz
C <sub>oss</sub>	Output Capacitance		4620			$V_{GS} = 0V, V_{DS} = -1.0V, f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		940			$V_{GS} = 0V$ , $V_{DS} = -44V$ , $f = 1.0MHz$
C <sub>oss</sub> eff.	Effective Output Capacitance		1530			$V_{GS} = 0V$ , $V_{DS} = 0V$ to -44V $\oplus$

### **Source-Drain Ratings and Characteristics**

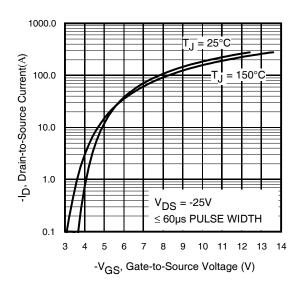
	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current			-42		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			-280		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			-1.3	٧	$T_J = 25^{\circ}C$ , $I_S = -42A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		61	92	ns	$T_J = 25^{\circ}C, I_F = -42A, V_{DD} = -28V$
Q <sub>rr</sub>	Reverse Recovery Charge		150	220	nC	di/dt = -100Α/μs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsion	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			



 $(V) \ \ \, \text{tueuno} \ \ \, \text{top} \ \ \, \frac{15V}{-15V} \ \ \, \frac{-15V}{-10V} \ \ \, \frac{-8.0V}{-7.0V} \ \ \, \frac{-8.0V}{-7.0V} \ \ \, \frac{-8.0V}{-7.0V} \ \ \, \frac{-5.5V}{-5.5V} \ \ \, \frac{-5.5V}{-5.5V} \ \ \, \frac{-5.5V}{-4.5V} \ \ \, \frac{-4.5V}{-4.5V} \ \ \, \frac{-15V}{-4.5V} \$ 

Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



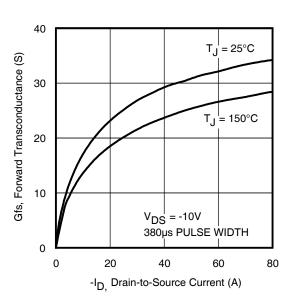
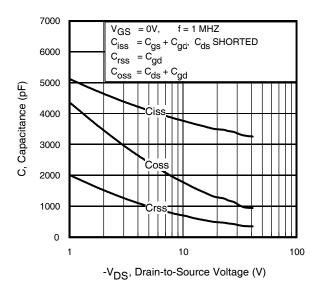
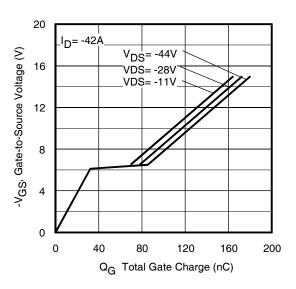


Fig 3. Typical Transfer Characteristics

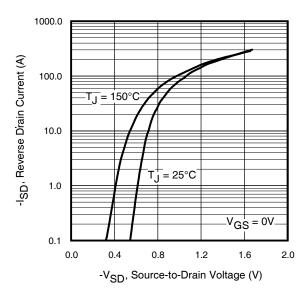
Fig 4. Typical Forward Transconductance Vs. Drain Current



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

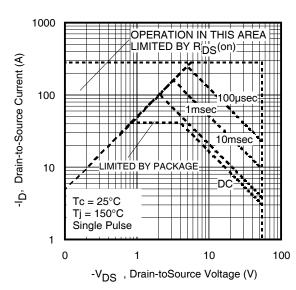
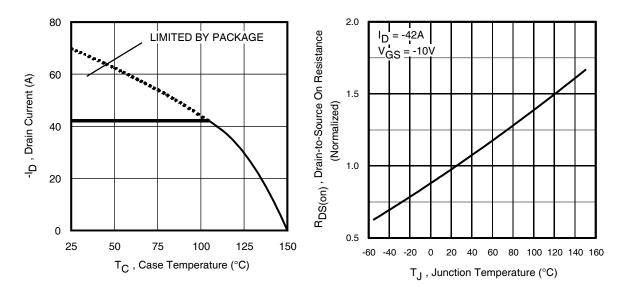


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

**Fig 10.** Normalized On-Resistance Vs. Temperature

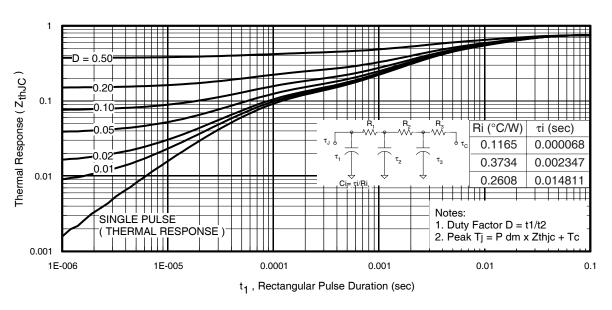


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

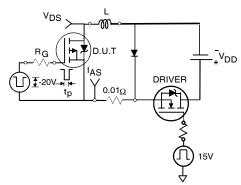


Fig 12a. Unclamped Inductive Test Circuit

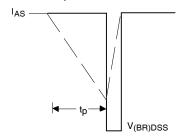


Fig 12b. Unclamped Inductive Waveforms

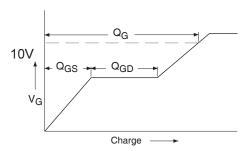
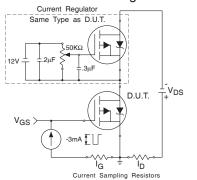
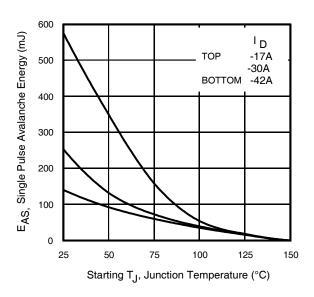


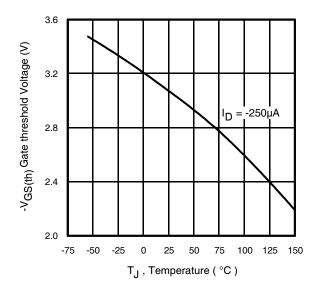
Fig 13a. Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit 6



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



**Fig 14.** Threshold Voltage Vs. Temperature www.irf.com

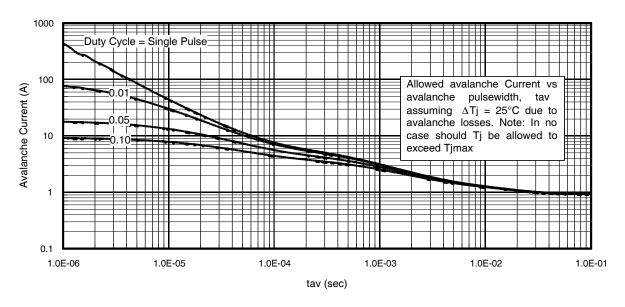


Fig 15. Typical Avalanche Current Vs. Pulsewidth

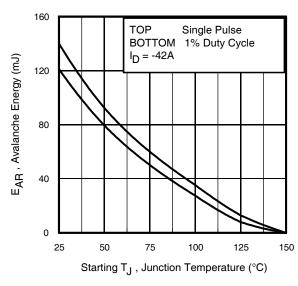


Fig 16. Maximum Avalanche Energy Vs. Temperature

#### Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{imax}$ . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long  $asT_{jmax}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed T<sub>imax</sub> (assumed as 25°C in Figure 15, 16).

 $t_{av}$  = Average time in avalanche.

 $D = Duty cycle in avalanche = t_{av} \cdot f$ 

 $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

$$\begin{split} P_{D~(ave)} &= 1/2~(~1.3 \cdot BV \cdot I_{av}) = \triangle T/~Z_{thJC} \\ I_{av} &= 2\triangle T/~[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS~(AR)} &= P_{D~(ave)} \cdot t_{av} \end{split}$$

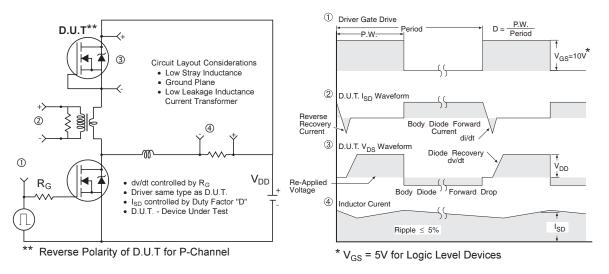


Fig 17. Peak Diode Recovery dv/dt Test Circuit for P-Channel HEXFET® Power MOSFETs

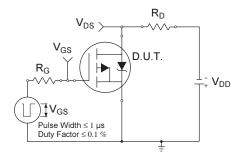


Fig 18a. Switching Time Test Circuit

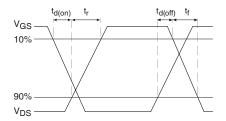
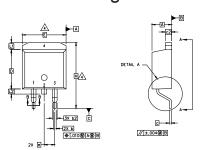
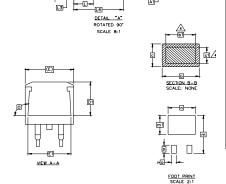


Fig 18b. Switching Time Waveforms

### D<sup>2</sup>Pak Package Outline (Dimensions are shown in millimeters (inches))







#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE WOLD FLASH, WOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. DIMENSION 61 AND 61 APPLY TO BASE METAL ONLY.

5. CONTROLLING DIMENSION: INCH.

S	DIMENSIONS							
M B O	MILLIM	ETERS	INC	INCHES				
L	MIN.	MAX.	MIN.	MAX.	E S			
Α	4.06	4.83	.160	.190				
A1	0.00	0.254	.000	.010				
ь	0.51	0.99	.020	.039				
ь1	0.51	0.89	.020	.035	4			
b2	1,14	1.78	.045	.070				
С	0.38	0.74	.015	.029				
c1	0.38	0.58	.015	.023	4			
c2	1,14	1.65	.045	.065				
D	8.51	9.65	.335	.380	3			
D1	6.86		.270					
E	9.65	10.67	.380	.420	3			
E1	6.22		.245					
e	2.54	BSC	.100	BSC				
Н	14.61	15.88	.575	.625				
L	1.78	2.79	.070	.110				
L1		1.65		.065				
L2	1.27	1.78	.050	.070				
L3	0.25	BSC	.010	BSC				
L4	4.78	5.28	.188	.208				
m	17.78		.700					
m1	8.89		.350					
n	11.43		.450					
0	2.08		.082					
р	3.81		.150					
R	0.51	0.71	.020	.028				
0	90,	93*	90*	93*				
				<u> </u>				

#### LEAD ASSIGNMENTS

#### **HEXFET**

1.- GATE 2, 4.- DRAIN 3.- SOURCE

#### IGBTs, CoPACK

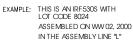
1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

#### DIODES

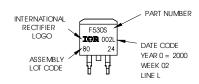
1.- ANODE \*
2, 4.- CATHODE
3.- ANODE

\* PART DEPENDENT.

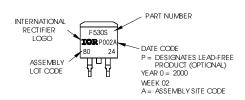
# D<sup>2</sup>Pak Part Marking Information



Note: "P" in assembly line position indicates "Lead-Free"

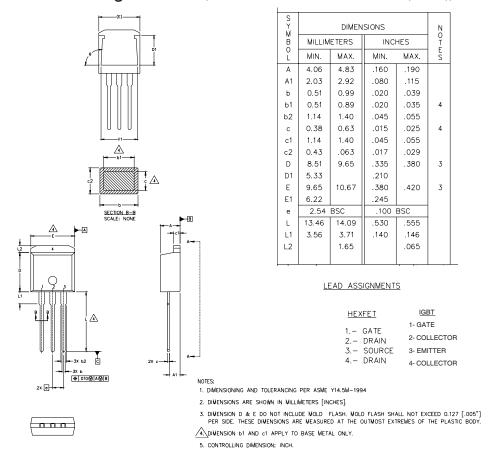




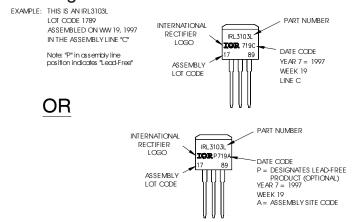


# International TOR Rectifier

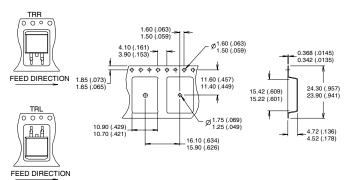
### TO-262 Package Outline (Dimensions are shown in millimeters (inches))

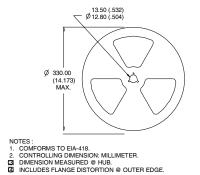


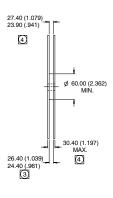
### TO-262 Part Marking Information



# D<sup>2</sup>Pak Tape & Reel Information







#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{Jmax}$ , starting  $T_J$  = 25°C, L = 0.16mH ⑥  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = -42A,  $V_{GS}$  =-10V. Part not recommended for use above this value. ②
- ③ Pulse width  $\leq$  1.0ms; duty cycle  $\leq$  2%.
- $\ \, \oplus \,\, C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$  .
- Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- This value determined from sample failure population. 100% tested to this value in production.
- This is applied to D<sup>2</sup>Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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TAC Fax: (310) 252-7903 Visit us at www.irf.com for sales contact information. 08/05

Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

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